# Karakterizacija nanostruktura: električna, optička i strukturna

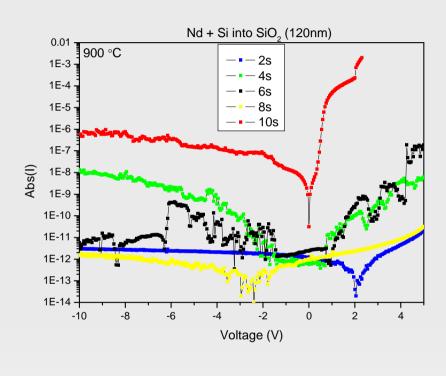
- > Osnovna: Strujno-naponska (I-V) i kapacitivno-naponska (C-V) mjerenja; Ovisnost o temperaturi;
- > Tranzijentna spektroskopija dubokih nivoa (DLTS)
- > Priprema uzoraka sa nanostrukturama za električna mjerenja (diode, MOS strukture)

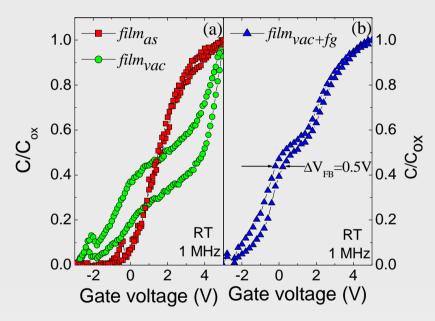


I-V



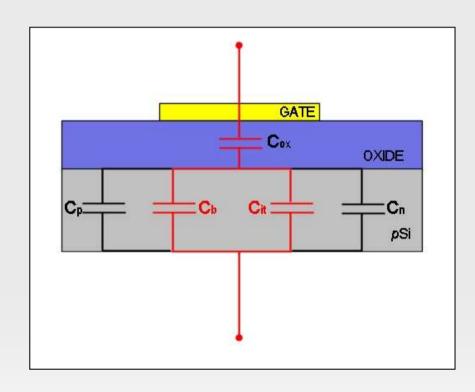
C-V, DLTS

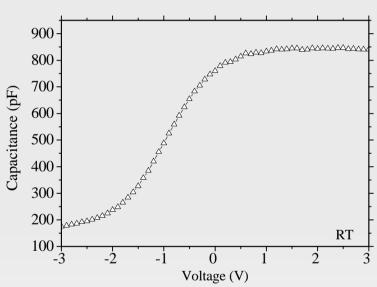


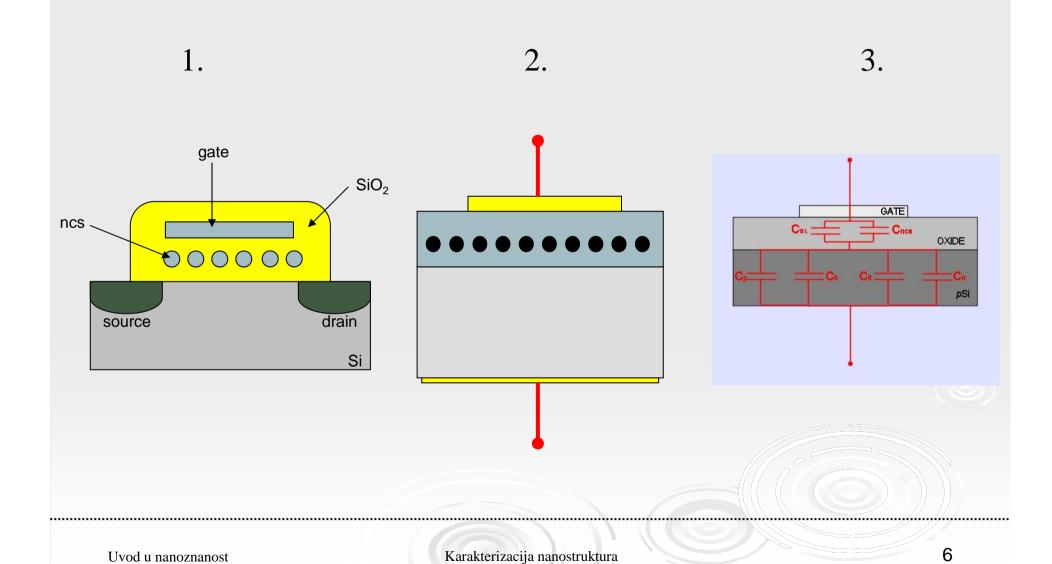


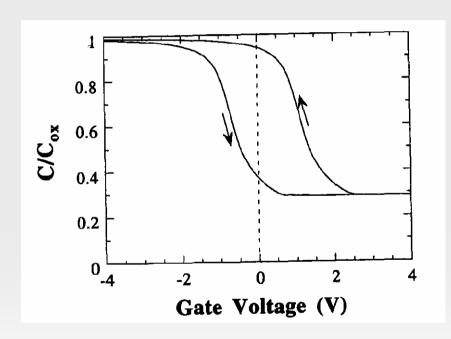
I-V

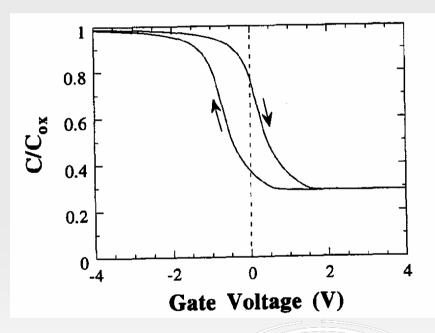
$$\Delta V_{FB} = \frac{e d_{QD}}{\epsilon_{ox}} (t_{ox} + \frac{\epsilon_{ox}}{\epsilon_{Ge}} R_{QD})$$

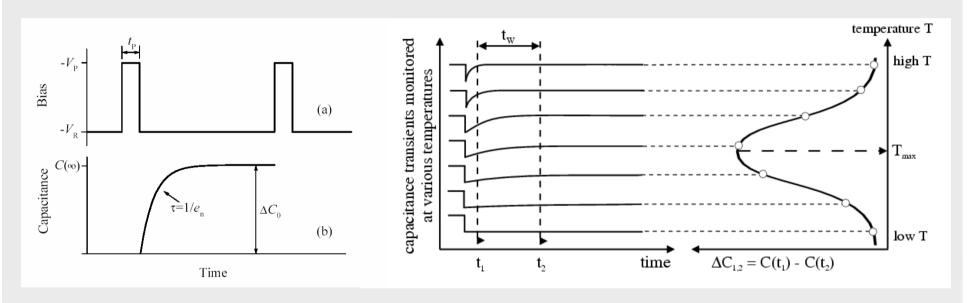




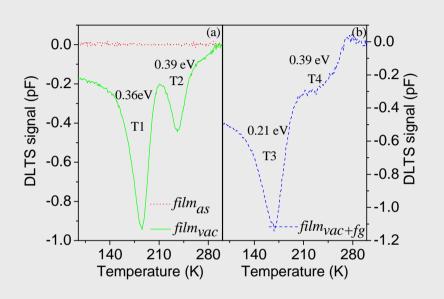


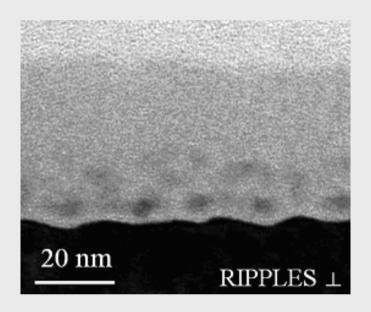






Tranzijentna spektroskopija dubokih nivoa





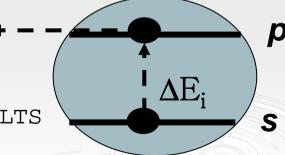
$$e_n = \gamma_n \sigma_n T^2 e^{\frac{\Delta E_a}{kT}}$$

$$\Delta E = E$$

$$\Delta E_i = E_{n=2} - E_{n=1}$$

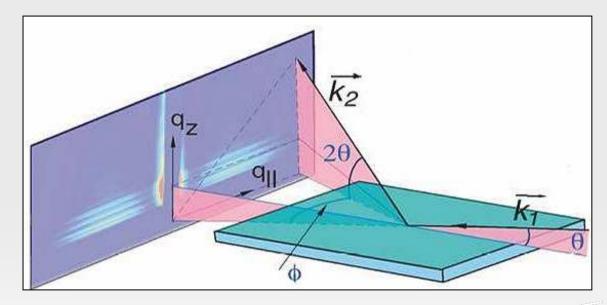
$$E_n = \frac{\hbar^2 n^2 \pi^2}{2m(2R_{QD})^2}$$

Detected by DLTS



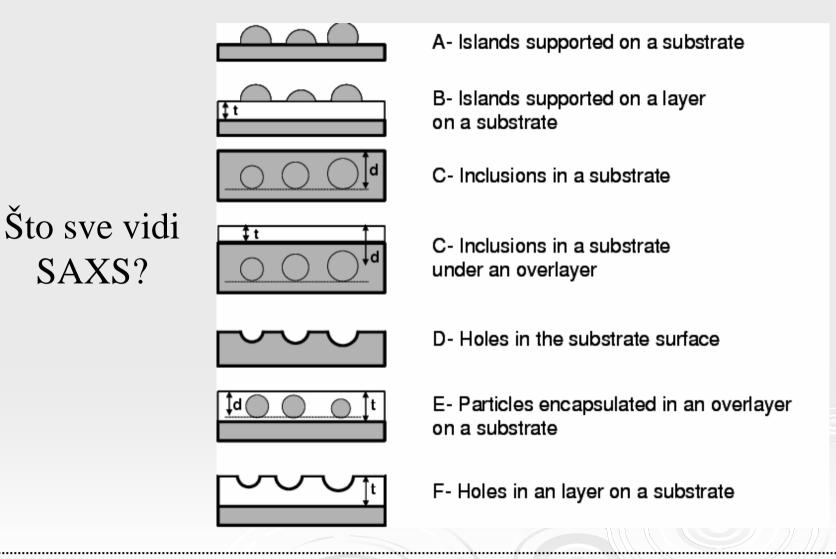
#### Strukturna karakterizacija

- Osnovna karakterizacija je još uvijek TEM!!!
- STM, AFM ...
- Raspršenje X-zraka (SAXS, GISAXS...)

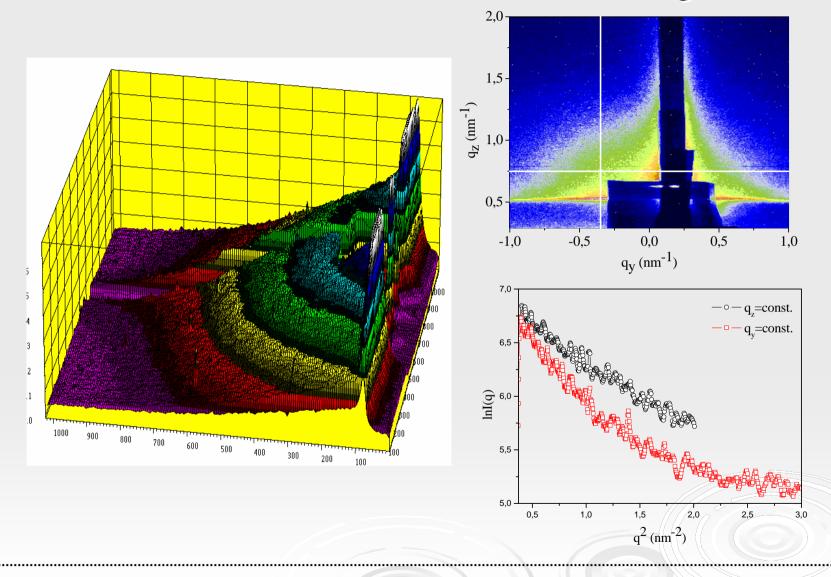


Sinkrotron Elettra, Trst  $\rightarrow$  Small Angle X-ray Scattering  $\lambda$ =0.154 nm; 8 keV; 2D CCD 1024x1024; 0.5 < d < 1.5 m

#### Strukturna karakterizacija



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### Optička karakterizacija

• Fotoluminiscencija (PL) is a process in which a substance absorbs photons (electromagnetic radiation) and then re-radiates photons. Quantum mechanically, this can be described as an excitation to a higher energy state and then a return to a lower energy state accompanied by the emission of a photon. This is one of many forms of luminescence (light emission) and is distinguished by photoexcitation (excitation by photons), hence the prefix photo-. The period between absorption and emission is typically extremely short, in the order of 10 nanoseconds.



#### Optička karakterizacija

